



Title of Change:	Final Test Platform Conversion from ETS364 to Advantest T2000
Proposed Changed Material First Ship Date:	08 Oct 2020 or earlier if approved by customer
Current Material Last Order Date:	N/A <i>Orders received after the Current Material Last Order Date expiration are to be considered as orders for new changed material as described in this PCN. Orders for current (unchanged) material after this date will be per mutual agreement and current material inventory availability.</i>
Current Material Last Delivery Date:	N/A <i>The Current Material Last Delivery Date may be subject to change based on build and depletion of the current (unchanged) material inventory</i>
Product Category:	Active components – Integrated circuits
Contact information:	Contact your local ON Semiconductor Sales Office or Bill.Fontes@onsemi.com
PCN Samples Contact:	Contact your local ON Semiconductor Sales Office to place sample order or <PCN.samples@onsemi.com>. Sample requests are to be submitted no later than 45 days after publication of this change notification. Samples delivery timing will be subject to request date, sample quantity and special customer packing/label requirements.
Sample Availability Date:	09 Oct 2019
PPAP Availability Date:	15 Nov 2019
Additional Reliability Data:	Contact your local ON Semiconductor Sales Office or Bill.Fontes@onsemi.com
Type of Notification:	This is a Final Product/Process Change Notification (FPCN) sent to customers. FPCNs are issued 12 months prior to implementation of the change or earlier upon customer approval. ON Semiconductor will consider this proposed change and it's conditions acceptable, unless an inquiry is made in writing within 45 days of delivery of this notice. To do so, contact PCN.Support@onsemi.com.
Change Category	
Category	Type of Change
Packing/Shipping	Packing/shipping specification change
Equipment	Change in final test equipment type that uses a different technology
Description and Purpose:	
Qualification of Advantest T2000 platform as additional capacity at final test.	
Test handler and test flow are unchanged.	
Minor changes to reel packaging (box window to view label, protective tape material, dessicant type).	
There are no product material changes as a result of this change.	
There is no product marking change as a result of this change.	
Reason / Motivation for Change:	Change benefit for customer: Improved manufacturing capacity Risk for late release for customer: Possible supply constraints Quality improvement: Yes, more modern test equipment.



Anticipated impact on fit, form, function, reliability, product safety or manufacturability:	The device has been qualified and validated based on the same Product Specification. The device has successfully passed the qualification tests. Potential impacts can be identified, but due to testing performed by ON Semiconductor in relation to the PCN, associated risks are verified and excluded. No anticipated impacts.	
Sites Affected:		
ON Semiconductor Sites		External Foundry/Subcon Sites
ON Semiconductor Carmona, Philippines		None
Marking of Parts/ Traceability of Change:	Date code	
Reliability Data Summary:		
Final test equipment change. No reliability testing is applicable.		
Electrical Characteristics Summary:		
Electrical characteristics are not impacted.		
Please see attached Tester Correlation Report.		
To view attachments: 1. Download pdf copy of the PCN to your computer 2. Open the downloaded pdf copy of the PCN 3. Click on the paper clip icon available on the menu provided in the left/bottom portion of the screen to reveal the Attachment field 4. Then click on the attached file/s		
List of Affected Parts:		
Note: Only the standard (off the shelf) part numbers are listed in the parts list. Any custom parts affected by this PCN are shown in the customer specific PCN addendum in the PCN email notification, or on the <u>PCN Customized Portal</u>.		
Current Part Number	New Part Number	Qualification Vehicle
NCV7718CDQR2G	N/A	NCV7728DPR2G
NCV7718BDQR2G	N/A	NCV7728DPR2G
NCV7728DPR2G	N/A	NCV7728DPR2G
NCV7728DPR2G	N/A	NCV7728DPR2G